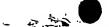
II S Departme	nt of Cor	nmerce Patent and	Trademark Office		Atty D	ocket No.		Applicati	on No.	
U.S. Department of Commerce, Patent and Trademark Office						NS-5127 US			10/054,653	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT						Applicant(s)			Confirmation No.	
Substitute PTO Form 1449					Constantin Bulucea			9448		
MM 0 3 Mg.									Group	
(MAY (3 2 E)					Filing Date January 18, 2002			2814		
THE TRADES	£/					7 18, 2002		2014		
*Examiner	<u></u>	Document	U.S. P	atent Documents		<u> </u>		Filing	Date If	
Initial		Number	Date	Name		Class	Subclass	Appropriate		
	AA									
	AB							-		
	AC		91							
	AD			•	·					
	AE	-								
	AF									
	AG									
	AH									
	AI									
	AJ		<u></u>							
	AK							-	_	
	·		Foreign	Patent Document	ts					
								Translation		
		Document	Date	Country	1	Class	Subclass	Yes	No	
	A'L									
	AM							<u> </u>		
	AN									
	AO								<u> </u>	
	AP									
		OTHER A	RT (Including Au	thor, Title, Date,	Pertinen	Pages, Etc	c.)		L	
1- 17	AQ							Power SO	Cs,"	
bir		Takeuchi et al, "A New Multiple Transistor Design Methodology for High Speed Low Power SC IEDM Technical Digest, December 2001, pages 22.6.1 - 22.6.7								
	AR `									
	AS	0								
Examiner 2	2	h	Date Considered	d 9	131	05				
EXAMINER:	Initial in conform	f reference consider mance and not consi	ed, whether or no dered. Include co	ot citation is in co	nforman	e with MP	EP 609; Draw ation to applic	line throug	gh	



		4				·····		7	cet 1 of 2	
U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.			Application No.		
					NS-512	27 US	10/054,653			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant			Confirmation No.		
(Use several sheets if necessary)					Constantin Bulucea			9448		
() () () () () () () () () ()						Filing Date			Group	
	(JAN 2 3 2003)						January 18, 2002			
P. P	45/		U.S.	Patent Documents	1			<u></u>		
*Examme	ASS	Document	Date	Name	 :	Class	Subclass	1	Date If	
Initial		Number	03/95	Weitzel et al.		257	. 355	Appro	opriate	
DE	AA	5,399,893	 		· ·		ļ		··-	
0F	AB	5,497,028	03/96	Ikeda et al.		257	531			
DI	AC	6,100,770	08/00	Litwin et al.		331	117 FE			
DF	AD	6,166,404	12/00	Imoto et al.		257	279			
	ĄĘ							<u> </u>	<u>:</u>	
		·	Foreig	n Patent Documen	ts					
								Trans	lation	
		Document	Date .	Country		Class	Subclass	Yes	No	
A	AF	6-61446	03/1994	Japan					Х	
6	AG									
	· · · · · ·	OTHER	ART (Including	Author, Title, Date	, Pertiner	nt Pages, E	tc.)	•		
DF	АН	Symposium on C	Circuits and Syste	OS VCO Tuned by ms, 28 – 31 May 2	000, pp.	I-315 – I -	318.			
	AI	Grove, <u>Physics a</u>	nd Technology o	f Semiconductor D	<u>evices</u> (J	ohn Wiley	& Sons), 196	7, pp. 263 –	305.	
	AJ			ields on the Breako 14 ,1967, pp. 157 -		tage of Pla	nar Silicon <i>p-i</i>	n Junction,"	' IEEE	
	AK .			p-n Junctions: Cha lid-State Electronic				ge Regions	Under	
	AL	Kral, et al., "RF Conference, 199		rs with Switched T	uning,"]	Procs. IEE	E Custom Inte	grated Circu	uits	
	AM	Lee, <u>The Design of CMOS Radio-Frequency Integrated Circuits</u> (Cambridge Univ. Press), 1998, pp. 3 41 and 504 – 514.								
	AN.		, "Voltage-Sensiti 1958, pp. 72 – 82.	ive Semiconductor	Capacito	ors," <u>1958</u>	IRE Wescon C	Conf. Rec., I	Part 3,	
DP	AO	Moll, "Variable - 36.	Capacitance With	Large Capacity C	hange," <u>I</u>	RE Wesco	n Conf. Rec.,	Vol. 3, 1959	9, pp. 32	
Examiner 0	<u></u>	eli:	Date Consider	ed 9/	310.	<u>.</u>				
*EXAMINER:	Initial i	f reference conside	ered, whether or n	not citation is in con	nformano	e with MP	EP 609; Draw	line throug	h	
citation if not in	n confor	mance and not con	sidered. Include	copy of this form v	vith your	communic	ation to applic	ant.		

		8 12 ·							eet 2 of
U.S. Department of Commerce, Patent and Trademark Office					Atty D	ocket No.	Application No.		
					NS-512	27 US	10/054,653		
DATE ON DISCLOSURE STATEMENT BY APPLICANT					Applicant			Confirmation No	
(Vse several sheets if necessary)					Constantin Bulucea			9448	
JAN 2 3 2003 w				Filing Date ·			Group		
U.S. Patent Documents			January 18, 2002			2814			
TRADEN	MARK		U.S. Pat	tent Documents	<u>'</u>	,			
Examiner		Document		· Class Subclass		Filing Date It			
Initial	A A	Number	Date	Ivaine	· · · · · ·	Class	Subciass	Appro	opriate
	AA							- 	
	. AB								
	AC	,							
···	AD								-
	AE					<u> </u>		1	<u> </u>
			Foreign P	atent Document	is 	 -		T	
		1				· 			slation
		Document	. Date	Country		Class	Subclass	Yes	No
	AF				·				ļ
	AG							<u> </u>	<u></u>
		OTHER A	RT (Including Aut	thor, Title, Date	, Pertiner	nt Pages, E	tc.)		
DF	AH	Ng, Complete Guide to Semiconductor Devices (McGraw Hill), 1995, pp. 11 - 22.							
(:	ΑI	Razavi, Design of	Analog CMOS Int	tegrated Circuits	(McGra	w Hill), 20	01, pp. 495 –	525.	
	AJ		-Depletion Breakd , March 1979, pp.		Silicon-I	Dioxide/Sil	licon MOS Ca	pacitors," II	EEE .
	AK	Rusu et al., "Reve Electronics, Vol. 2			e in Silic	on Gate-Co	ontrolled Diod	es," <u>Solid-S</u>	tate
	AL .	Sedra, et al., Micro	oelectronic Circuit	s, (4th ed., Oxfo	rd Univ.	Press), 199	98, p. 382.		
:	AM		Three Terminal Var lectron Devices, V				OS Technology	," <u>IEEE</u>	
1	AN	Warner, Jr., et al., 1983, pp. 320 – 32	<u>Transistors – Fund</u> 21.	lamentals for the	e Integrat	ted-Circuit	Engineer (Joh	n Wiley &	Sons),
DR.	AO	Wong et al., "A W 779.	ide Tuning Range	Gated Varactor	," <u>IEEE</u> J	. Solid Sta	te Circs, May	2000, pp. 7	73 –
examiner /	\Box		Date Considered		•	7	1310	(